Abstracts

Measurement-Based Model Parameters for Quasi-Optical Electron Device Arrays (Short Papers)

L.B. Sjogren, H.-X.L. Liu, X.-H. Qin, C.W. Domier and N.C. Luhmann, Jr.. "Measurement-Based Model Parameters for Quasi-Optical Electron Device Arrays (Short Papers)." 1995 Transactions on Microwave Theory and Techniques 43.4 (Apr. 1995, Part I [T-MTT]): 899-901.

Impedance element values for a Schottky beam control diode array are obtained by curve-fitting quasioptical reflection coefficient measurements to a series RLC array model. The model provides a good representation of the array behavior. Parameters of Schottky varactor arrays tested to-date are summarized. The technique should be applicable to other quasioptical arrays, as well.

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